

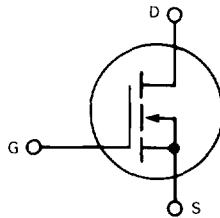
MRF161

The RF MOSFET Line

**N-CHANNEL ENHANCEMENT-MODE
RF POWER FIELD-EFFECT TRANSISTOR**

... designed for wideband large-signal amplifier and oscillator applications in the 2.0 to 400 MHz range.

- Guaranteed 28 Volt, 400 MHz Performance
Output Power = 5.0 Watts
Minimum Gain = 11 dB
Efficiency = 50% (Typical)
- Small-Signal and Large-Signal Characterization
- 100% Tested for Load Mismatch At All Phase Angles
With 30:1 VSWR
- Low Noise Figure — 3.0 dB (Typ) at 100 mA, 400 MHz
- Excellent Thermal Stability, Ideally Suited For Class A Operation
- Facilitates Manual Gain Control, ALC and Modulation Techniques



MAXIMUM RATINGS

Rating	Symbol	Value	Unit
Drain-Source Voltage	V_{DS}	65	Vdc
Drain-Gate Voltage ($R_{GS} = 1.0 \text{ M}\Omega$)	V_{DGR}	65	Vdc
Gate-Source Voltage	V_{GS}	±40	Vdc
Drain Current — Continuous	I_D	0.9	Adc
Total Device Dissipation (at $T_C = 25^\circ\text{C}$ Derate above 25°C)	P_D	17.5 0.10	Watts W/°C
Storage Temperature Range	T_{stg}	65 to +150	°C
Operating Junction Temperature	T_J	200	°C

THERMAL CHARACTERISTICS

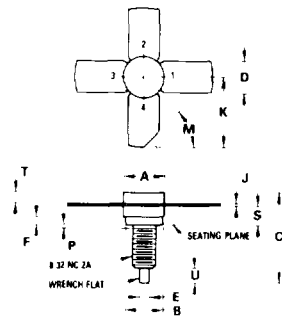
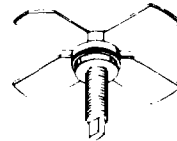
Characteristic	Symbol	Max	Unit
Thermal Resistance, Junction to Case	$R_{\theta JC}$	10	°C/W

Handling and Packaging — MOS devices are susceptible to damage from electrostatic charge. Reasonable precautions in handling and packaging MOS devices should be observed.

5.0 W 2.0-400 MHz

**N-CHANNEL MOS
BROADBAND RF POWER**

FET



STYLE 3
PIN 1 SOURCE
2 GATE
3 SOURCE
4 DRAIN

DIM	MILLIMETERS		INCHES	
	MIN	MAX	MIN	MAX
A	7.06	7.26	0.278	0.286
B	6.20	6.50	0.244	0.256
C	14.99	16.51	0.590	0.650
D	5.46	5.96	0.215	0.235
E	1.40	1.65	0.055	0.065
F	1.52	—	0.060	—
J	0.08	0.17	0.003	0.007
K	11.05	—	0.435	—
M	45	NOM	45	NOM
P	—	1.27	—	0.050
S	3.00	3.25	0.118	0.128
T	1.40	1.77	0.055	0.070
U	2.92	3.68	0.115	0.145

CASE 244-04

MRF161

ELECTRICAL CHARACTERISTICS ($T_C = 25^\circ\text{C}$ unless otherwise noted)

Characteristic	Symbol	Min	Typ	Max	Unit
OFF CHARACTERISTICS					
Drain-Source Breakdown Voltage ($V_{GS} = 0, I_D = 5.0 \text{ mA}$)	$V_{(BR)DSS}$	65	—	—	Vdc
Zero Gate Voltage Drain Current ($V_{DS} = 28 \text{ V}, V_{GS} = 0$)	I_{DSS}	—	—	1.0	mAdc
Gate-Source Leakage Current ($V_{GS} = 40 \text{ V}, V_{DS} = 0$)	I_{GSS}	—	—	1.0	μAdc
ON CHARACTERISTICS					
Gate Threshold Voltage ($V_{DS} = 10 \text{ V}, I_D = 10 \text{ mA}$)	$V_{GS(th)}$	1.0	3.0	6.0	Vdc
Forward Transconductance ($V_{DS} = 10 \text{ V}, I_D = 100 \text{ mA}$)	g_{fs}	80	110	—	mmhos
DYNAMIC CHARACTERISTICS					
Input Capacitance ($V_{DS} = 28 \text{ V}, V_{GS} = 0, f = 1.0 \text{ MHz}$)	C_{iss}	—	7.0	—	pF
Output Capacitance ($V_{DS} = 28 \text{ V}, V_{GS} = 0, f = 1.0 \text{ MHz}$)	C_{oss}	—	9.7	—	pF
Reverse Transfer Capacitance ($V_{DS} = 28 \text{ V}, V_{GS} = 0, f = 1.0 \text{ MHz}$)	C_{rss}	—	2.3	—	pF
FUNCTIONAL CHARACTERISTICS (Figure 1)					
Noise Figure ($V_{DS} = 28 \text{ Vdc}, I_D = 100 \text{ mA}, f = 400 \text{ MHz}$, $Z_S = 67.6 + j14.1, Z_L = 14.5 + j25.7$)	NF	—	3.0	—	dB
Common Source Power Gain ($V_{DD} = 28 \text{ Vdc}, P_{out} = 5.0 \text{ W}, f = 400 \text{ MHz}, I_{DQ} = 50 \text{ mA}$)	G_{ps}	11	13.5	—	dB
Drain Efficiency ($V_{DD} = 28 \text{ Vdc}, P_{out} = 5.0 \text{ W}, f = 400 \text{ MHz}, I_{DQ} = 50 \text{ mA}$)	η	45	50	—	%
Electrical Ruggedness ($V_{DD} = 28 \text{ Vdc}, P_{out} = 5.0 \text{ W}, f = 400 \text{ MHz}, I_{DQ} = 50 \text{ mA}$, VSWR 30:1 at All Phase Angles)	ψ	No Degradation in Output Power			

FIGURE 1 — 400 MHz TEST CIRCUIT

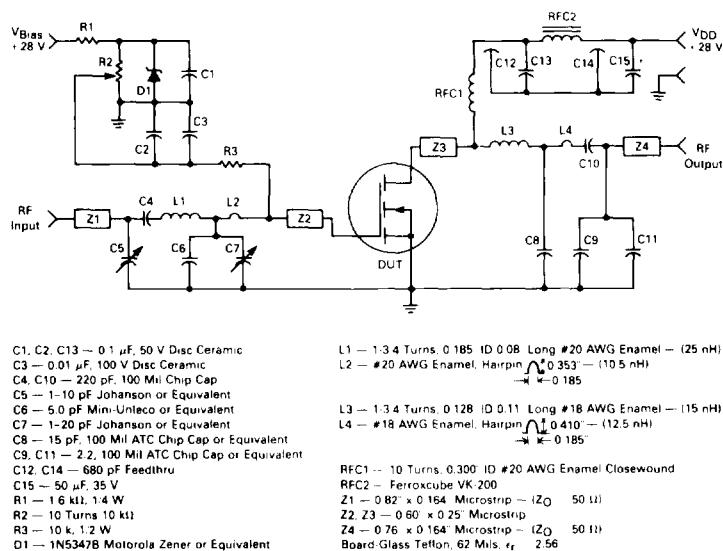


FIGURE 2 — OUTPUT POWER versus INPUT POWER

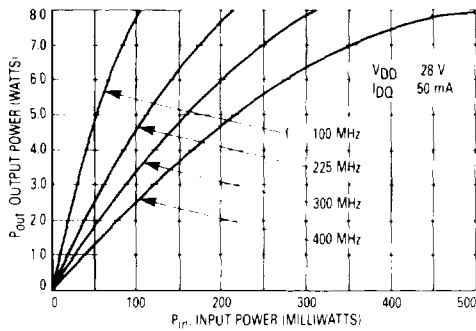


FIGURE 3 — OUTPUT POWER versus INPUT POWER

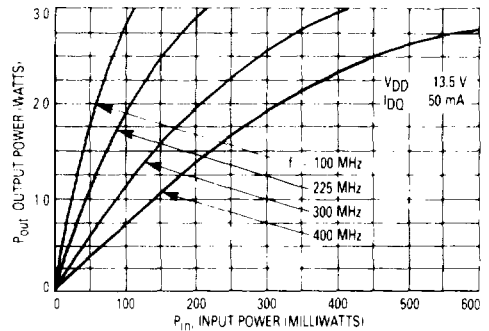
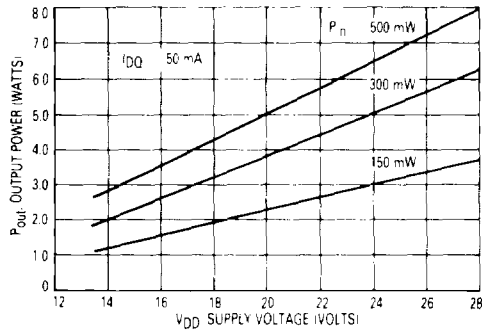
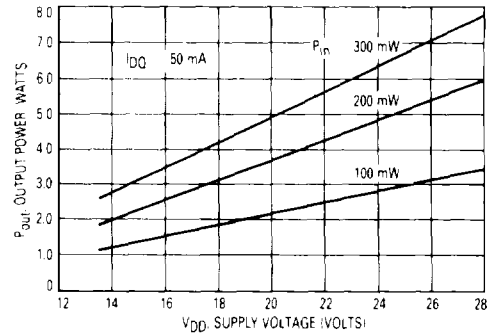
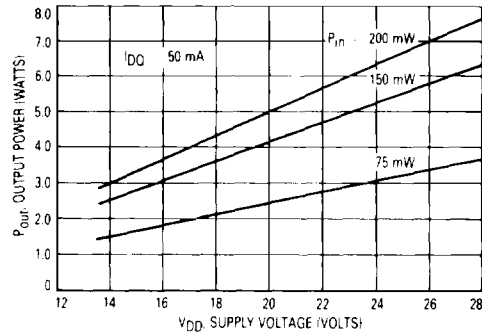
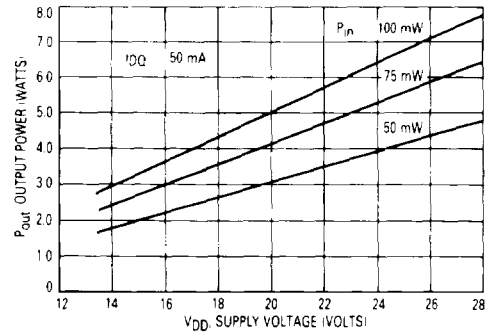
FIGURE 4 — OUTPUT POWER versus SUPPLY VOLTAGE
 $f = 400 \text{ MHz}$ FIGURE 5 — OUTPUT POWER versus SUPPLY VOLTAGE
 $f = 300 \text{ MHz}$ FIGURE 6 — OUTPUT POWER versus SUPPLY VOLTAGE
 $f = 225 \text{ MHz}$ FIGURE 7 — OUTPUT POWER versus SUPPLY VOLTAGE
 $f = 100 \text{ MHz}$ 

FIGURE 8 — OUTPUT POWER versus GATE VOLTAGE

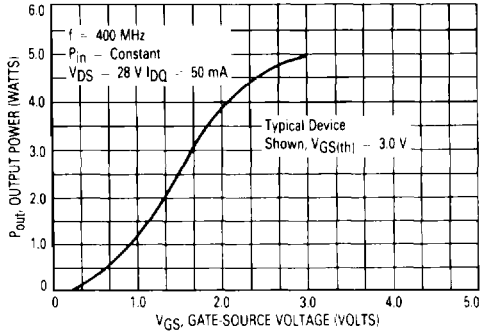


FIGURE 9 — DRAIN CURRENT versus GATE VOLTAGE (TRANSFER CHARACTERISTICS)

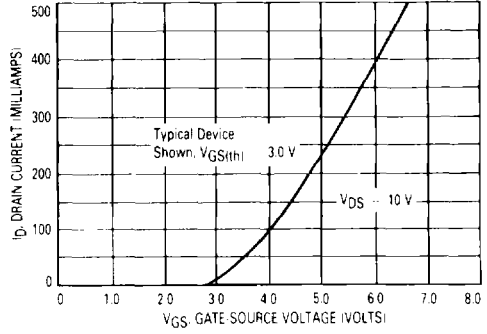


FIGURE 10 — GATE-SOURCE VOLTAGE versus CASE TEMPERATURE

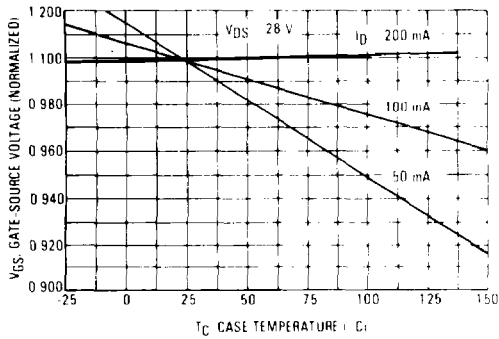
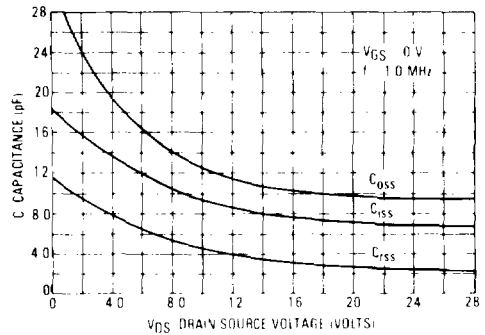


FIGURE 11 — CAPACITANCE versus VOLTAGE



MRF161

FIGURE 12 — MAXIMUM RATED FORWARD BIASED
SAFE OPERATING AREA

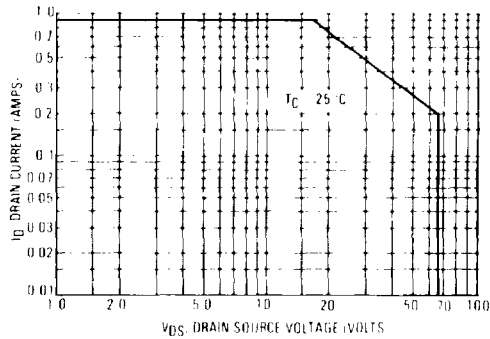
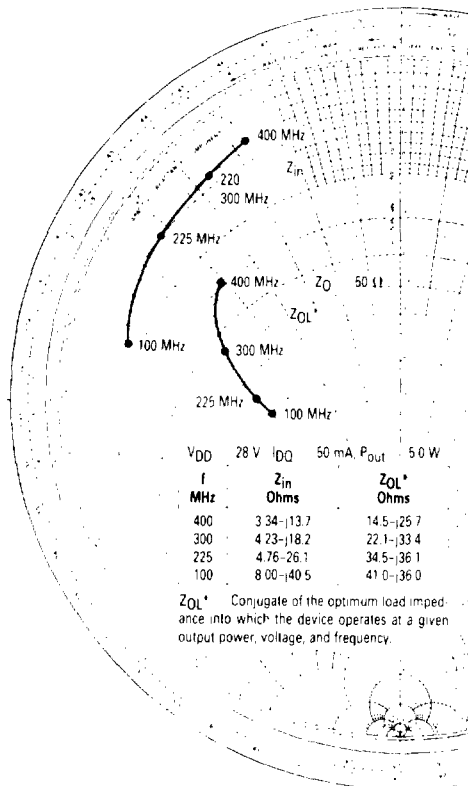


FIGURE 13 — LARGE-SIGNAL SERIES EQUIVALENT INPUT AND
OUTPUT IMPEDANCE, Z_{in} , Z_{OL}^*

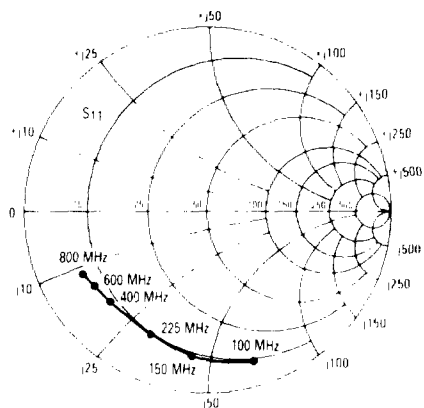


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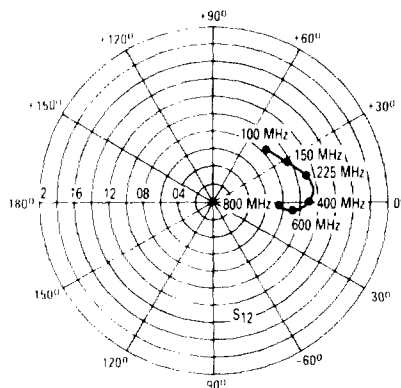
FIGURE 14 — COMMON SOURCE SCATTERING PARAMETERS
50 OHM SYSTEM
 $V_{DS} = 28 \text{ V}$, $I_D = 250 \text{ mA}$

f (MHz)	S ₁₁		S ₂₁		S ₁₂		S ₂₂	
	S ₁₁	∠ φ	S ₂₁	∠ φ	S ₁₂	∠ φ	S ₂₂	∠ φ
2.0	1.000	-1.69	13.64	178	0.002	62	0.947	-1.84
5.0	1.000	-4.63	13.60	176	0.005	69	0.945	-4.00
10	0.997	-8.95	13.70	173	0.010	80	0.941	-7.92
20	0.989	-17.49	13.36	167	0.022	73	0.929	-15.8
30	0.977	-26	13.07	162	0.032	71	0.915	-23
40	0.968	-34	12.76	156	0.042	67	0.902	-30
50	0.949	-42	12.31	151	0.050	61	0.885	-37
60	0.930	-49	11.88	146	0.058	57	0.866	-43
70	0.913	-56	11.45	141	0.066	53	0.846	-49
80	0.897	-62	10.96	137	0.072	50	0.831	-55
90	0.885	-68	10.50	133	0.078	46	0.817	-60
100	0.867	-74	10.00	129	0.081	43	0.800	-65
110	0.853	-78	9.54	125	0.085	40	0.787	-69
120	0.838	-84	8.92	122	0.090	37	0.775	-74
130	0.819	-88	8.75	119	0.093	35	0.762	-78
140	0.812	-92	8.30	116	0.096	31	0.755	-81
150	0.800	-96	7.95	113	0.098	28	0.742	-86
160	0.785	-99	7.54	111	0.100	26	0.735	-89
170	0.775	-103	7.25	109	0.102	24	0.728	-93
180	0.765	-105	6.85	106	0.103	23	0.725	-96
190	0.755	-108	6.60	104	0.104	21	0.720	-98
200	0.740	-111	6.20	100	0.106	18	0.719	-99
225	0.735	-116	5.71	96	0.110	16	0.715	-103
250	0.723	-121	5.17	92	0.112	12	0.708	-107
275	0.720	-124	4.80	89	0.113	10	0.706	-110
300	0.716	-128	4.43	85	0.112	7.0	0.706	-113
325	0.715	-130	4.17	83	0.111	4.0	0.717	-115
350	0.715	-133	3.87	79	0.111	3.0	0.720	-117
375	0.715	-135	3.67	76	0.111	1.0	0.728	-118
400	0.711	-137	3.43	74	0.109	0	0.729	-119
425	0.714	-139	3.25	71	0.104	0	0.738	-120
450	0.717	-140	3.11	69	0.104	-2.0	0.743	-121
475	0.719	-141	2.95	67	0.103	-3.0	0.757	-122
500	0.722	-142	2.81	65	0.102	-4.0	0.770	-122
525	0.723	-144	2.69	62	0.099	-6.0	0.777	-123
550	0.727	-144	2.55	61	0.097	-6.0	0.787	-123
575	0.729	-145	2.46	59	0.097	-7.0	0.802	-124
600	0.733	-146	2.37	57	0.094	-7.0	0.814	-124
625	0.734	-147	2.29	55	0.090	-8.0	0.824	-126
650	0.740	-148	2.19	54	0.087	-8.0	0.830	-127
675	0.749	-149	2.12	53	0.085	-6.0	0.849	-127
700	0.758	-149	2.07	51	0.084	-6.0	0.879	-127
725	0.761	-150	1.99	49	0.082	-5.0	0.886	-127
750	0.763	-151	1.93	48	0.081	-4.0	0.905	-127
775	0.765	-151	1.90	48	0.079	-3.0	0.919	-128
800	0.770	-152	1.83	46	0.076	-1.0	0.921	-128

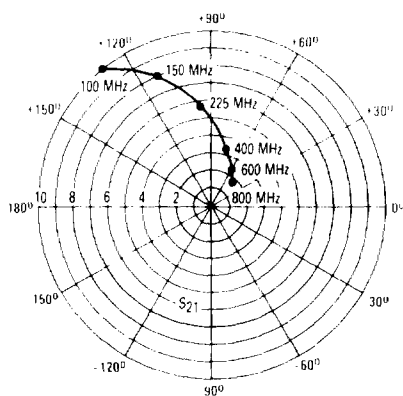
**FIGURE 15 — S_{11} , INPUT REFLECTION COEFFICIENT
versus FREQUENCY**
 $V_{DS} = 28 \text{ V}$, $I_D = 250 \text{ mA}$



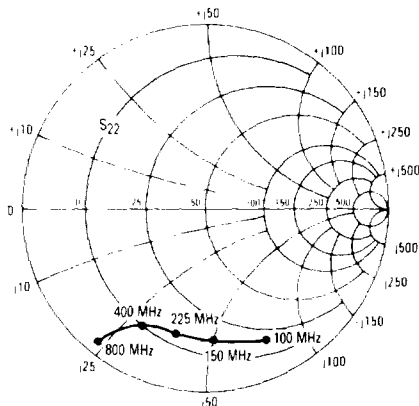
**FIGURE 16 — S_{12} , REVERSE TRANSMISSION COEFFICIENT
versus FREQUENCY**
 $V_{DS} = 28 \text{ V}$, $I_D = 250 \text{ mA}$



**FIGURE 17 — S_{21} , FORWARD TRANSMISSION COEFFICIENT
versus FREQUENCY**
 $V_{DS} = 28 \text{ V}$, $I_D = 250 \text{ mA}$



**FIGURE 18 — S_{22} , OUTPUT REFLECTION COEFFICIENT
versus FREQUENCY**
 $V_{DS} = 28 \text{ V}$, $I_D = 250 \text{ mA}$



DESIGN CONSIDERATIONS

The MRF161 is a RF power N-Channel enhancement mode field-effect transistor (FET) designed especially for UHF power amplifier and oscillator applications. Motorola RF MOS FETs feature a vertical structure with a planar design, thus avoiding the processing difficulties associated with V-groove vertical power FETs.

Motorola Application Note AN211A, FETs in Theory and Practice, is suggested reading for those not familiar with the construction and characteristics of FETs.

The major advantages of RF power FETs include high gain, low noise, simple bias systems, relative immunity from thermal runaway, and the ability to withstand severely mismatched loads without suffering damage. Power output can be varied over a wide range with a low power dc control signal, thus facilitating manual gain control, ALC and modulation.

DC BIAS

The MRF161 is an enhancement mode FET and, therefore, does not conduct when drain voltage is applied. Drain current flows when a positive voltage is applied to the gate. See Figure 9 for a typical plot of drain current versus gate voltage. RF power FETs require forward bias for optimum performance. The value of quiescent drain current (I_{DQ}) is not critical for many applications. The MRF161 was characterized at $I_{DQ} = 50$ mA, which is the suggested minimum value of I_{DQ} . For special applications such as linear amplification, I_{DQ} may have to be selected to optimize the critical parameters.

The gate is a dc open circuit and draws no current. Therefore, the gate bias circuit may generally be just a

simple resistive divider network. Some applications may require a more elaborate bias system.

GAIN CONTROL

Power output of the MRF161 may be controlled from its rated value down to zero (negative gain) by varying the dc gate voltage. This feature facilitates the design of manual gain control, AGC-ALC and modulation systems. (See Figure 8.)

AMPLIFIER DESIGN

Impedance matching networks similar to those used with bipolar UHF transistors are suitable for the MRF161. See Motorola Application Note AN721, Impedance Matching Networks Applied to RF Power Transistors. The higher input impedance of RF MOS FETs helps ease the task of broadband network design. Both small signal scattering parameters and large signal impedances are provided. While the s-parameters will not produce an exact design solution for high power operation, they do yield a good first approximation. This is an additional advantage of RF MOS power FETs.

RF power FETs are triode devices and, therefore, not unilateral. This, coupled with the very high gain of the MRF161, yields a device capable of self oscillation. Stability may be achieved by techniques such as drain loading, input shunt resistive loading, or output to input feedback. Two port parameter stability analysis with the MRF161 s-parameters provides a useful tool for selection of loading or feedback circuitry to assure stable operation. See Motorola Application Note AN215A for a discussion of two port network theory and stability.

FIGURE 19 — 400 MHz TEST CIRCUIT

